







CD74HC4075, CD54HC4075 SCHS210H - NOVEMBER 1998 - REVISED JUNE 2021

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# CDx4HC4075 Triple 3-Input OR Gates

### **1** Features

- **Buffered** inputs
- Wide operating voltage range: 2 V to 6 V •
- Wide operating temperature range: ٠ -55°C to +125°C
- Supports fanout up to 10 LSTTL loads
- Significant power reduction compared to LSTTL logic ICs

## 2 Applications

- User fewer inputs to monitor error signals
- Combine active-low enable signals ٠

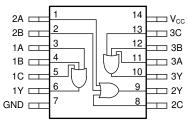
# **3 Description**

This device contains three independent 3-input OR gates. Each gate performs the Boolean function Y = A + B + C in positive logic.

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Device Information <sup>(1)</sup>							
PART NUMBER PACKAGE BODY SIZE (NOM)							
CD74HC4075M	SOIC (14)	8.70 mm × 3.90 mm					
CD74HC4075E	PDIP (14)	19.30 mm × 6.40 mm					
CD74HC4075NS SO (14) 10.20 mm × 5.30 mm							
CD74HC4075PW TSSOP (14) 5.00 mm × 4.40 mm							
CD54HC4075F	CDIP (14)	21.30 mm × 7.60 mm					
CD54HC4075FK	LCCC (20)	8.90 mm × 8.90 mm					

(1) For all available packages, see the orderable addendum at the end of the data sheet.



**Functional pinout** 





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## **4 Revision History**

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

C	hanges from Revision G (June 2006) to Revision H (June 2021)	Page
•	Updated to new data sheet standards	1
•	Moved the HCT devices to a standalone data sheet (SCHS408)	1
	R <sub>0JA</sub> increased for the D (86 to 133.6 °C/W), PW (133 to 151.7 °C/W), and NS (76 to 122.6 °C/W) packa and decreased for the N package (80 to 61.3 °C/W)	ages



# **5** Pin Configuration and Functions

2A 🗖	10	14	
2B 🗖	2	13	3C
1A 🗆	3	12	3B
1B 🗖	4	11	3A
1C 🗖	5	10	3Y
1Y 🗖	6	9	2Y
GND	7	8	2C

#### D, N, NS, PW, or J Package 14-Pin SOIC, PDIP, SO, TSSOP, or CDIP Top View

	2B	2A		V <sub>cc</sub>	3C	
	03	2	1 1	20	 19	
1A	∷:4				18 🖾	3B
NC	∷⊧5				17 🖽	NC
1B	∷⊧6				16∷	ЗA
NC	∷;7				15∷	NC
1C	∷:8				14 😄	3Y
	9 m	10 m	11 ጠ	12	13 m	
	1Y (	GNE	) NC	) 2C	2Y	
	FI	ΚP	ac	kag	ge	
	20	-Pi	n L	_C(	CC	
Top View						

### **Pin Functions**

	PIN				
NAME	D, N, NS, PW, or J	FK	I/O	DESCRIPTION	
2A	1	2	Input	Channel 2, Input A	
2B	2	3	Input	Channel 2, Input B	
1A	3	4	Input	Channel 1, Input A	
1B	4	6	Input	Channel 1, Input B	
1C	5	8	Input	Channel 1, Input C	
1Y	6	9	Output	Channel 1, Output Y	
GND	7	10	_	Ground	
2C	8	12	Input	Channel 2, Input C	
2Y	9	13	Output	Channel 2, Output Y	
3Y	10	14	Output	Channel 3, Output Y	
3A	11	16	Input	Channel 3, Input A	
3B	12	18	Input	Channel 3, Input B	
3C	13	19	Input	Channel 3, Input C	
V <sub>CC</sub>	14	20	_	Positive Supply	
NC		1, 5, 7, 11, 15, 17	_	Not internally connected	



### 6 Specifications

### 6.1 Absolute Maximum Ratings

over operating free-a	air temperature range	(unless otherwise	noted) <sup>(1)</sup>

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage		-0.5	7	V
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>	$V_{I} < -0.5 V \text{ or } V_{I} > V_{CC} + 0.5 V$		±20	mA
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	$V_{O} < -0.5 V \text{ or } V_{O} > V_{CC} + 0.5 V$		±20	mA
lo	Continuous output current	$V_{O} = 0$ to $V_{CC}$		±25	mA
	Continuous current through $V_{CC}$ or GND			±50	mA
т	Junction temperature <sup>(3)</sup>	Plastic package		150	°C
IJ		Hermetic package or die		175	°C
	Lead temperature (soldering 10s)	SOIC - lead tips only		300	°C
T <sub>stg</sub>	Storage temperature		-65	150	°C

(1) Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

(3) Guaranteed by design.

### 6.2 ESD Ratings

			VALUE	UNIT
CD74HC40	75 IN D (SOIC) AND N (PDIP) PACKAGES			
M	Electrostatio displarga	Human-body model (HBM), per ANSI/ESDA/ JEDEC JS-001 <sup>(1)</sup>	±1000	M
V <sub>(ESD)</sub>	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>	±250	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			
V <sub>IH</sub>	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			V
		V <sub>CC</sub> = 6 V	4.2			
		V <sub>CC</sub> = 2 V			0.5	
VIL	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35	V
	N	V <sub>CC</sub> = 6 V			1.8	
VI	Input voltage		0		V <sub>CC</sub>	V
Vo	Output voltage		0		V <sub>CC</sub>	V
		V <sub>CC</sub> = 2 V			1000	
t <sub>t</sub>	Input transition time	V <sub>CC</sub> = 4.5 V			500	ns
		V <sub>CC</sub> = 6 V			400	
T <sub>A</sub>	Operating free-air temperature	CD74HC4075	-55		125	°C



#### 6.4 Thermal Information

		CD74HC4075					
THERMAL METRIC <sup>(1)</sup>		PW (TSSOP)	N (PDIP)	D (SOIC)	NS (SOP)	UNIT	
		14 PINS	14 PINS	14 PINS	14 PINS		
R <sub>θJA</sub>	Junction-to-ambient thermal resistance	151.7	61.3	133.6	122.6	°C/W	
R <sub>0JC(top)</sub>	Junction-to-case (top) thermal resistance	79.4	49.0	89.0	81.8	°C/W	
R <sub>θJB</sub>	Junction-to-board thermal resistance	94.7	41.0	89.5	83.8	°C/W	
$\Psi_{JT}$	Junction-to-top characterization parameter	25.2	28.7	45.5	45.4	°C/W	
$\Psi_{JB}$	Junction-to-board characterization parameter	94.1	40.8	89.1	83.4	°C/W	
R <sub>0JC(bot)</sub>	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	N/A	°C/W	

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

### **6.5 Electrical Characteristics**

over operating free-air temperature range; typical values measured at  $T_A = 25^{\circ}C$  (unless otherwise noted).

							Opera	ting free	air tem	peratur	e (T <sub>A</sub> )			
P	ARAMETER	TEST CO	NDITIONS	Vcc		25°C		<b>-40°</b>	C to 85	°C	–55°(	C to 125	5°C	UNIT
					MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
				2 V	1.9			1.9			1.9			
			I <sub>OH</sub> = –20 μΑ	4.5 V	4.4			4.4			4.4			
	High-level	V <sub>I</sub> = V <sub>IH</sub> or	h., ,	6 V	5.9			5.9			5.9			
V <sub>OH</sub>	output voltage	V <sub>IL</sub>	I <sub>OH</sub> = –4 mA	4.5 V	3.98			3.84			3.7			V
			I <sub>OH</sub> = -5.2 mA	6 V	5.48			5.34			1.9    4.4    5.9			
				2 V			0.1			0.1				
			I <sub>OL</sub> = 20 μΑ	4.5 V			0.1			0.1				
VOL	Low-level output			6 V			0.1			0.1			0.1	v
	voltage	VIL	I <sub>OL</sub> = 4 mA	4.5 V			0.26			0.33			0.4	
			I <sub>OL</sub> = 5.2 mA	6 V			0.26			0.33			0.4	
I <sub>I</sub>	Input leakage current	$V_{I} = V_{CC}$ or		6 V			±0.1			±1			±1	μA
I <sub>CC</sub>	Supply current	$V_{I} = V_{CC}$ or 0	I <sub>O</sub> = 0	6 V			2			20			40	μA
Ci	Input capacitance			5 V			10			10			10	pF

### 6.6 Switching Characteristics

over operating free-air temperature range; typical values measured at TA = 25°C (unless otherwise noted).

				TEST	TEST	Operating free-air temperature (T <sub>A</sub> )									
	PARAMETER		то	CONDITIO	V <sub>cc</sub>	25°C –40°C to 85°C –55°C to				C to 12	25°C	UNIT			
				NS		MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
					2 V			100			125			150	
		A, B, or C	Y	C <sub>L</sub> = 50 pF	4.5 V			20			25	3	30		
t <sub>pd</sub>	Propagation delay				6 V			17			21			26	ns
		A, B, or C	Y	C <sub>L</sub> = 15 pF	5 V		8								



over exercting free air temperature renge: t	unical values measured at TA = 25°C	(uplace otherwise noted)
over operating free-air temperature range; to	vpical values measured at TA – 25 C	(unless otherwise noted).

				0 , 11												
					TEST	TEST		Operating free-air temperature (T <sub>A</sub> )								
		PARAMETER	FROM	то	CONDITIO V <sub>CC</sub>		25°C		<b>-40°</b>	C to 8	5°C	–55°C	C to 12	25°C	UNIT	
					NS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX		
						2 V			75			95			110	
	t <sub>t</sub>	Transition-time	nsition-time Y $C_L = 50 \text{ pF}$ 4.5 V			15			19			22	ns			
						6 V			13			16			19	

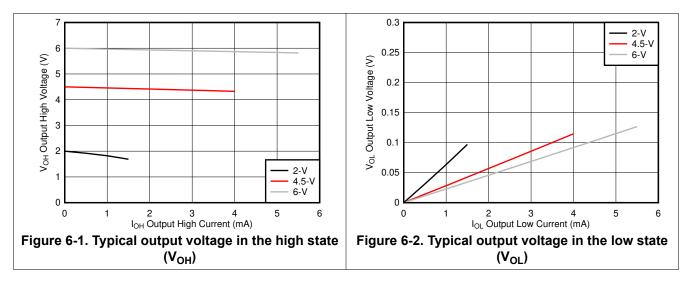
### 6.7 Operating Characteristics

over operating free-air temperature range; typical values measured at  $T_A = 25^{\circ}C$  (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	UNIT
Cpc	Power dissipation capacitance per gate	No load	2 V to 6 V		26		pF

### 6.8 Typical Characteristics

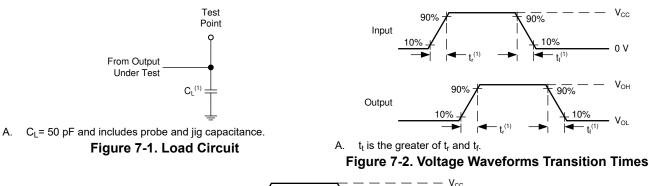
T<sub>A</sub> = 25°C

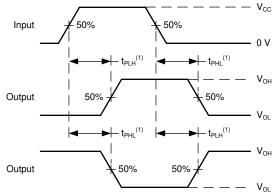




### 7 Parameter Measurement Information

- Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR ≤ 1 MHz, Z<sub>O</sub> = 50 Ω, t<sub>t</sub> < 6 ns.</li>
- The outputs are measured one at a time, with one input transition per measurement.





A. The maximum between  $t_{PLH}$  and  $t_{PHL}$  is used for  $t_{pd}$ .

#### Figure 7-3. Voltage Waveforms Propagation Delays

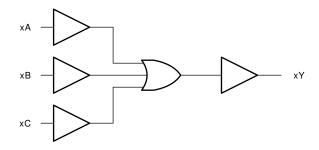


### 8 Detailed Description

#### 8.1 Overview

This device contains three independent 3-input OR gates. Each gate performs the Boolean function Y = A + B + C in positive logic.

#### 8.2 Functional Block Diagram



#### 8.3 Feature Description

#### 8.3.1 Balanced CMOS Push-Pull Outputs

A balanced output allows the device to sink and source similar currents. The drive capability of this device may create fast edges into light loads so routing and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. It is important for the output power of the device to be limited to avoid damage due to over-current. The electrical and thermal limits defined in the *Section 6.1* must be followed at all times.

The CD74HC4075 can drive a load with a total capacitance less than or equal to the maximum load listed in the *Section 6.6* connected to a high-impedance CMOS input while still meeting all of the datasheet specifications. Larger capacitive loads can be applied, however it is not recommended to exceed the provided load value. If larger capacitive loads are required, it is recommended to add a series resistor between the output and the capacitor to limit output current to the values given in the *Section 6.1*.

#### 8.3.2 Standard CMOS Inputs

Standard CMOS inputs are high impedance and are typically modeled as a resistor from the input to ground in parallel with the input capacitance given in the *Section 6.5*. The worst case resistance is calculated with the maximum input voltage, given in the *Section 6.1*, and the maximum input leakage current, given in the *Section 6.5*, using ohm's law ( $R = V \div I$ ).

Signals applied to the inputs need to have fast edge rates, as defined by the input transition time in the *Section* 6.3 to avoid excessive current consumption and oscillations. If a slow or noisy input signal is required, a device with a Schmitt-trigger input should be used to condition the input signal prior to the standard CMOS input.

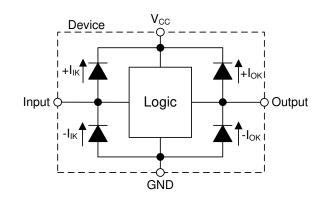


#### 8.3.3 Clamp Diode Structure

The inputs and outputs to this device have both positive and negative clamping diodes as depicted in Figure 8-1.

#### CAUTION

Voltages beyond the values specified in the Section 6.1 table can cause damage to the device. The recommended input and output voltage ratings may be exceeded if the input and output clampcurrent ratings are observed.



#### Figure 8-1. Electrical Placement of Clamping Diodes for Each Input and Output

#### 8.4 Device Functional Modes

	INPUTS		OUTPUT
А	В	С	Y
L	L	L	L
Н	Х	Х	Н
Х	Н	Х	Н
Х	Х	Н	Н

#### Table 8-1. Function Table



### 9 Application and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

#### 9.1 Application Information

In this application, one 3-input OR gates is used to combine overheat signals to control a fan as shown in *Figure 9-1*. The other two gates can be used for another application in the system, or the inputs can be grounded and the channels left unused.

This device is used to directly control the Enable pin of a fan driver. The fan driver requires only one input signal to be HIGH before being enabled, and should be disabled in the event that all signals go LOW. The 4-input OR gate function combines the four individual overheat signals into a single active-high enable signal.

#### 9.2 Typical Application

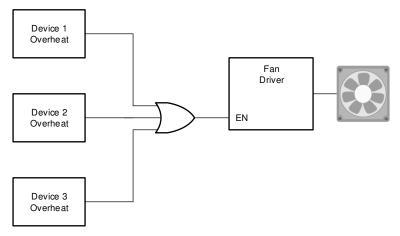


Figure 9-1. Typical application schematic

#### 9.2.1 Design Requirements

#### 9.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the Section 6.3. The supply voltage sets the device's electrical characteristics as described in the Section 6.5.

The supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the CD74HC4075 plus the maximum supply current,  $I_{CC}$ , listed in the Section 6.5. The logic device can only source or sink as much current as it is provided at the supply and ground pins, respectively. Be sure not to exceed the maximum total current through GND or  $V_{CC}$  listed in the Section 6.1.

Total power consumption can be calculated using the information provided in CMOS Power Consumption and  $C_{pd}$  Calculation.

Thermal increase can be calculated using the information provided in Thermal Characteristics of Standard Linear and Logic (SLL) Packages and Devices.



#### CAUTION

The maximum junction temperature,  $T_J(max)$  listed in the Section 6.1, is an additional limitation to prevent damage to the device. Do not violate any values listed in the Section 6.1. These limits are provided to prevent damage to the device.

#### 9.2.1.2 Input Considerations

Unused inputs must be terminated to either  $V_{CC}$  or ground. These can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input is to be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The resistor size is limited by drive current of the controller, leakage current into the CD74HC4075, as specified in the *Section 6.5*, and the desired input transition rate. A 10-k $\Omega$  resistor value is often used due to these factors.

The CD74HC4075 has standard CMOS inputs, so input signal edge rates cannot be slow. Slow input edge rates can cause oscillations and damaging shoot-through current. The recommended rates are defined in the *Section* 6.3.

Refer to the Section 8.3 for additional information regarding the inputs for this device.

#### 9.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the  $V_{OH}$  specification in the *Section 6.5*. Similarly, the ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the  $V_{OL}$  specification in the *Section 6.5*.

Unused outputs can be left floating. Do not connect outputs directly to V<sub>CC</sub> or ground.

Refer to Section 8.3 for additional information regarding the outputs for this device.

#### 9.2.2 Detailed Design Procedure

- 1. Add a decoupling capacitor from  $V_{CC}$  to GND. The capacitor needs to be placed physically close to the device and electrically close to both the  $V_{CC}$  and GND pins. An example layout is shown in the Section 11.
- Ensure the capacitive load at the output is ≤ 70 pF. This is not a hard limit, however it will ensure optimal performance. This can be accomplished by providing short, appropriately sized traces from the CD74HC4075 to the receiving device.
- Ensure the resistive load at the output is larger than (V<sub>CC</sub> / I<sub>O</sub>(max)) Ω. This will ensure that the maximum output current from the Section 6.1 is not violated. Most CMOS inputs have a resistive load measured in megaohms; much larger than the minimum calculated above.
- 4. Thermal issues are rarely a concern for logic gates, however the power consumption and thermal increase can be calculated using the steps provided in the application report, CMOS Power Consumption and Cpd Calculation

#### 9.2.3 Application Curves

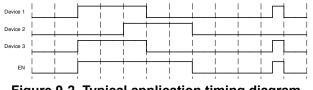


Figure 9-2. Typical application timing diagram



### **10 Power Supply Recommendations**

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Section 6.3*. Each  $V_{CC}$  terminal should have a bypass capacitor to prevent power disturbance. A 0.1-µF capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1-µF and 1-µF capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in *Figure 11-1*.



### 11 Layout

### **11.1 Layout Guidelines**

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.

#### 11.2 Layout Example

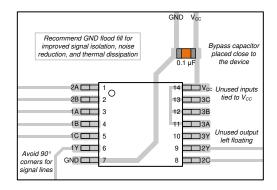


Figure 11-1. Example layout for the CD74HC4075



### 12 Device and Documentation Support

#### **12.1 Documentation Support**

#### 12.1.1 Related Documentation

For related documentation see the following:

- HCMOS Design Considerations
- CMOS Power Consumption and CPD Calculation
- Designing with Logic

#### **12.2 Support Resources**

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 12.3 Trademarks

TI E2E<sup>™</sup> is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

#### 12.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 12.5 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

### 13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



### **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
5962-87722012A	ACTIVE	LCCC	FK	20	55	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 87722012A CD54HC 4075FK	Samples
5962-8772201CA	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-8772201CA CD54HC4075F3A	Samples
CD54HC4075F3A	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-8772201CA CD54HC4075F3A	Samples
CD54HC4075FK	ACTIVE	LCCC	FK	20	55	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962- 87722012A CD54HC 4075FK	Samples
CD74HC4075E	ACTIVE	PDIP	Ν	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC4075E	Samples
CD74HC4075EE4	ACTIVE	PDIP	Ν	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC4075E	Samples
CD74HC4075M	OBSOLETE	SOIC	D	14		TBD	Call TI	Call TI	-55 to 125	HC4075M	
CD74HC4075M96	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-55 to 125	HC4075M	Samples
CD74HC4075MT	OBSOLETE	SOIC	D	14		TBD	Call TI	Call TI	-55 to 125	HC4075M	
CD74HC4075NSR	ACTIVE	SOP	NS	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC4075M	Samples
CD74HC4075PW	OBSOLETE	TSSOP	PW	14		TBD	Call TI	Call TI	-55 to 125	HJ4075	
CD74HC4075PWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-55 to 125	HJ4075	Samples
CD74HC4075PWT	OBSOLETE	TSSOP	PW	14		TBD	Call TI	Call TI	-55 to 125	HJ4075	

<sup>(1)</sup> The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design. **PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.



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<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF CD54HC4075, CD74HC4075 :

• Catalog : CD74HC4075

• Military : CD54HC4075

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications



Texas

STRUMENTS

### TAPE AND REEL INFORMATION





#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC4075M96	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
CD74HC4075NSR	SOP	NS	14	2000	330.0	16.4	8.45	10.55	2.5	12.0	16.2	Q1
CD74HC4075PWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



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# PACKAGE MATERIALS INFORMATION

7-Dec-2024



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC4075M96	SOIC	D	14	2500	367.0	367.0	38.0
CD74HC4075NSR	SOP	NS	14	2000	356.0	356.0	35.0
CD74HC4075PWR	TSSOP	PW	14	2000	356.0	356.0	35.0

### TEXAS INSTRUMENTS

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### TUBE



# - B - Alignment groove width

#### \*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	Τ (μm)	B (mm)
5962-87722012A	FK	LCCC	20	55	506.98	12.06	2030	NA
CD54HC4075FK	FK	LCCC	20	55	506.98	12.06	2030	NA
CD74HC4075E	N	PDIP	14	25	506	13.97	11230	4.32
CD74HC4075E	N	PDIP	14	25	506	13.97	11230	4.32
CD74HC4075EE4	N	PDIP	14	25	506	13.97	11230	4.32
CD74HC4075EE4	N	PDIP	14	25	506	13.97	11230	4.32

# FK 20

### 8.89 x 8.89, 1.27 mm pitch

# **GENERIC PACKAGE VIEW**

# LCCC - 2.03 mm max height

LEADLESS CERAMIC CHIP CARRIER

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





# **GENERIC PACKAGE VIEW**

# CDIP - 5.08 mm max height

CERAMIC DUAL IN LINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



# J0014A



# **PACKAGE OUTLINE**

### CDIP - 5.08 mm max height

CERAMIC DUAL IN LINE PACKAGE



NOTES:

- 1. All controlling linear dimensions are in inches. Dimensions in brackets are in millimeters. Any dimension in brackets or parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This package is hermitically sealed with a ceramic lid using glass frit.
- Index point is provided on cap for terminal identification only and on press ceramic glass frit seal only.
  Falls within MIL-STD-1835 and GDIP1-T14.



# J0014A

# **EXAMPLE BOARD LAYOUT**

# CDIP - 5.08 mm max height

CERAMIC DUAL IN LINE PACKAGE





# N (R-PDIP-T\*\*)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- $\triangle$  The 20 pin end lead shoulder width is a vendor option, either half or full width.



# **PW0014A**



# **PACKAGE OUTLINE**

# TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



# PW0014A

# **EXAMPLE BOARD LAYOUT**

# TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



# PW0014A

# **EXAMPLE STENCIL DESIGN**

# TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

9. Board assembly site may have different recommendations for stencil design.



<sup>8.</sup> Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

# **D0014A**



# **PACKAGE OUTLINE**

# SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm, per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
- 5. Reference JEDEC registration MS-012, variation AB.



# D0014A

# **EXAMPLE BOARD LAYOUT**

# SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



# D0014A

# **EXAMPLE STENCIL DESIGN**

# SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



### MECHANICAL DATA

#### PLASTIC SMALL-OUTLINE PACKAGE

#### 0,51 0,35 ⊕0,25⊛ 1,27 8 14 0,15 NOM 5,60 8,20 5,00 7,40 $\bigcirc$ Gage Plane ₽ 0,25 7 1 1,05 0,55 0-10 Δ 0,15 0,05 Seating Plane — 2,00 MAX 0,10PINS \*\* 14 16 20 24 DIM 10,50 10,50 12,90 15,30 A MAX A MIN 9,90 9,90 12,30 14,70 4040062/C 03/03

NOTES: A. All linear dimensions are in millimeters.

NS (R-PDSO-G\*\*)

**14-PINS SHOWN** 

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



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